

WHAT IS CLAIMED IS:

1. An IC measuring device for determining acceptance/rejection of timing between a data strobe and data outputted from an IC to be measured, the IC measuring device comprising:

a first timing generator for outputting a pair of judgment strobe pulses different in time point and in synchronism with a test cycle of the IC measuring device;

a first edge detector for detecting states of the data strobe at two time points within one test cycle on the basis of the pair of judgment strobe pulses different in time point and supplied by the first timing generator;

a second timing generator for outputting a pair of judgment strobe pulses different in time point but in synchronism with a test cycle of the IC measuring device;

a second edge detector for detecting states of the data at two time points within one test cycle on the basis of the pair of judgment strobe pulses different in time point and supplied by the second timing generator; and

a judgment section for determining acceptance/rejection of timing of the data with reference to the data strobe on the basis of the states of the data detected by the second edge detector and the states of the data strobe detected by the first edge detector.

2. The IC measuring device according to Claim 1, wherein a time interval between the pair of judgment strobe pulses outputted from the first timing generator and a time interval between the pair of judgment strobe pulses outputted by the second timing generator are set respectively in accordance with standards of the IC to be measured.

3. The IC measuring device according to Claim 1, wherein a relationship in accordance with the standards of the IC to be measured is established between timing at which the first timing generator outputs each of the judgment strobe pulses and timing at which the second timing generator outputs corresponding one of the judgment strobe pulses.

4. The IC measuring device according to Claim 1, including:

a plurality of circuit blocks each including the second timing generator, the second edge detector and the judgment section.

5. The IC measuring device according to Claim 4, wherein a relationship in accordance with the standards of the IC to be measured is established among judgment strobe pulses outputted from the second timing generators included in the circuit blocks.